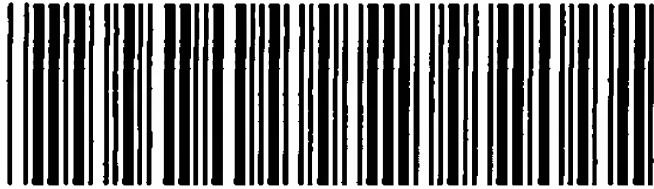


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/617,172	KIM ET AL.	
	Examiner	Art Unit	
	Tianjie Chen	2627	

SEARCHED			
Class	Subclass	Date	Examiner
Updated		5/4/2007	TJ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR